

FDP79N15 / FDPF79N15 150V N-Channel MOSFET

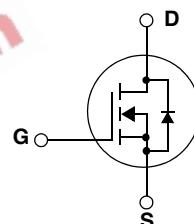
Features

- 79A, 150V, $R_{DS(on)} = 0.03\Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 56 nC)
- Low C_{rss} (typical 96pF)
- Fast switching
- Improved dv/dt capability

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



Absolute Maximum Ratings

Symbol	Parameter	FDP79N15	FDPF79N15	Unit
V_{DSS}	Drain-Source Voltage	150		V
I_D	Drain Current	- Continuous ($T_C = 25^\circ C$) - Continuous ($T_C = 100^\circ C$)	79 50	79* 50*
I_{DM}	Drain Current	- Pulsed	(Note 1)	316
V_{GSS}	Gate-Source voltage		± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	1669	mJ
I_{AR}	Avalanche Current	(Note 1)	79	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	46.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_D	Power Dissipation	($T_C = 25^\circ C$) - Derate above $25^\circ C$	463 3.7	38 0.3
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDP79N15	FDPF79N15	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.27	3.3	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	--	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP79N15	FDP79N15	TO-220	-	-	50
FDPF79N15	FDPF79N15	TO-220F	-	-	50

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$, $T_J = 25^\circ\text{C}$	150	--	--	V	
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, Referenced to 25°C	--	0.15	--	$\text{V}/^\circ\text{C}$	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 150\text{V}$, $V_{GS} = 0\text{V}$ $V_{DS} = 120\text{V}$, $T_C = 125^\circ\text{C}$	--	--	1 10	μA μA	
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{V}$, $V_{DS} = 0\text{V}$	--	--	100	nA	
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{V}$, $V_{DS} = 0\text{V}$	--	--	-100	nA	
On Characteristics							
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	3.0	--	5.0	V	
$R_{DS(\text{on})}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{V}$, $I_D = 39.5\text{A}$	--	0.025	0.03	Ω	
g_{FS}	Forward Transconductance	$V_{DS} = 40\text{V}$, $I_D = 39.5\text{A}$	(Note 4)	46	--	S	
Dynamic Characteristics							
C_{iss}	Input Capacitance	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1.0\text{MHz}$		--	2620	pF	
C_{oss}	Output Capacitance			--	730	pF	
C_{rss}	Reverse Transfer Capacitance			--	96	pF	
Switching Characteristics							
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 75\text{V}$, $I_D = 79\text{A}$ $R_G = 25\Omega$	(Note 4, 5)	--	50	112	ns
t_r	Turn-On Rise Time			--	200	410	ns
$t_{d(off)}$	Turn-Off Delay Time			--	55	120	ns
t_f	Turn-Off Fall Time			--	38	85	ns
Q_g	Total Gate Charge	$V_{DS} = 120\text{V}$, $I_D = 79\text{A}$ $V_{GS} = 10\text{V}$	(Note 4, 5)	--	56	73	nC
Q_{gs}	Gate-Source Charge			--	18	--	nC
Q_{gd}	Gate-Drain Charge			--	21	--	nC
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	79	--	A	
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	316	--	A	
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{V}$, $I_S = 79\text{A}$	--	--	1.4	V	
t_{rr}	Reverse Recovery Time	$V_{GS} = 0\text{V}$, $I_S = 79\text{A}$ $dI_F/dt = 100\text{A}/\mu\text{s}$	(Note 4)	--	136	--	ns
Q_{rr}	Reverse Recovery Charge			--	2.1	--	μC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $L = 0.357\text{mH}$, $I_{AS} = 79\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 79\text{A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

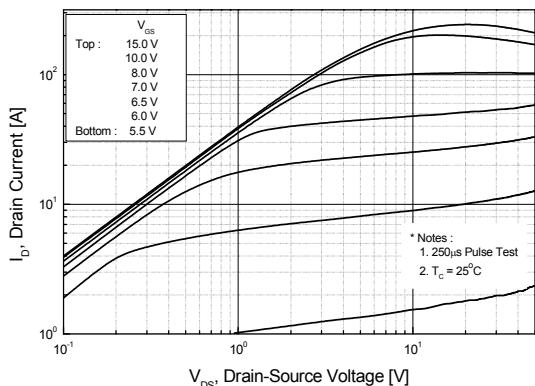


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

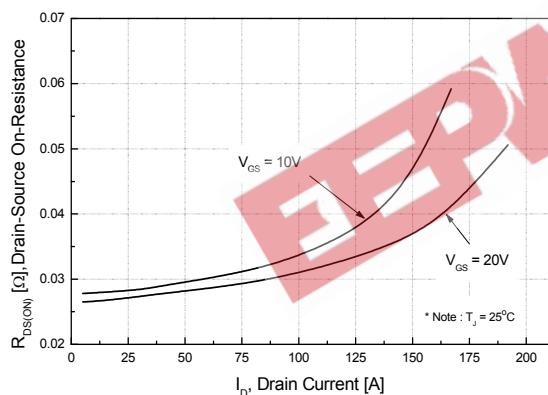


Figure 5. Capacitance Characteristics

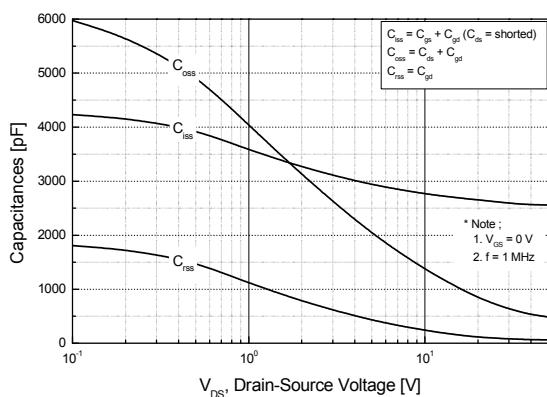


Figure 2. Transfer Characteristics

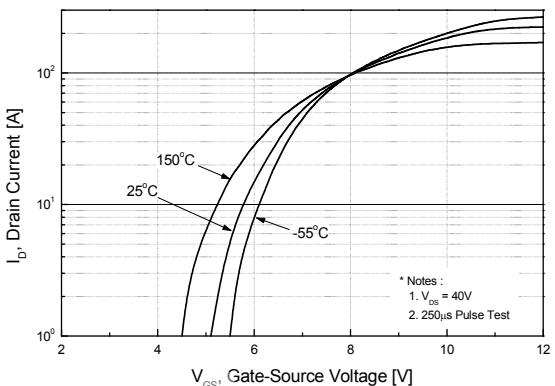


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

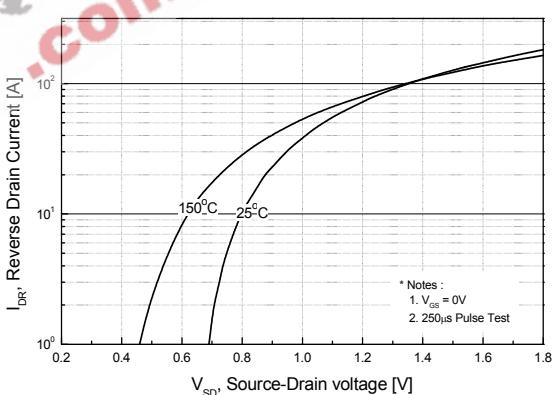
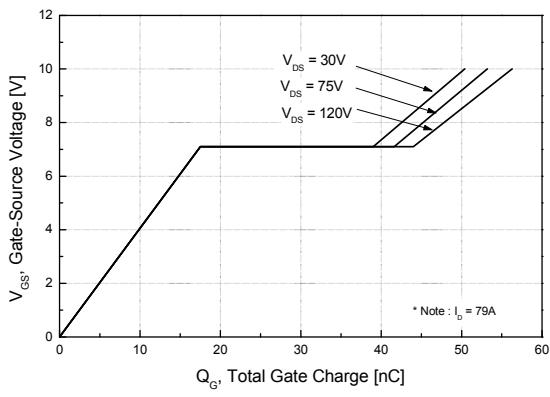


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

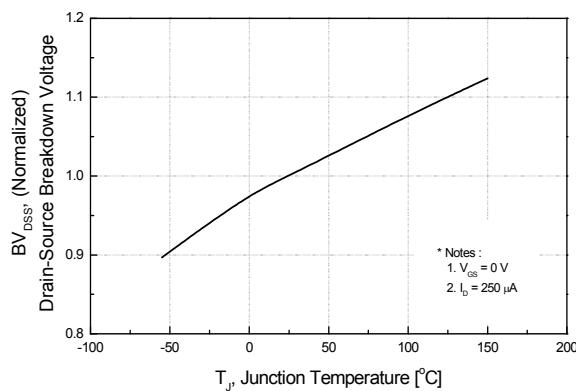


Figure 8. On-Resistance Variation vs. Temperature

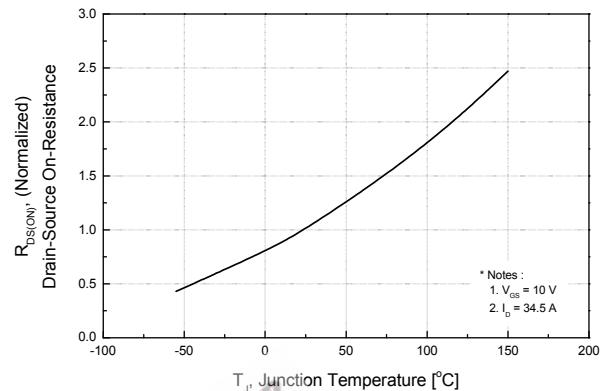


Figure 9-1. Maximum Safe Operating Area for FDP79N15

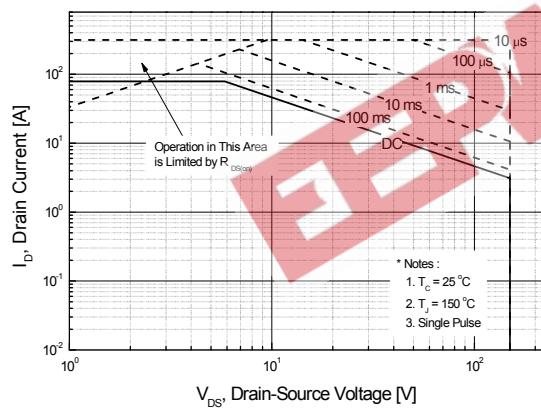


Figure 9-2. Maximum Safe Operating Area for FDPF79N15

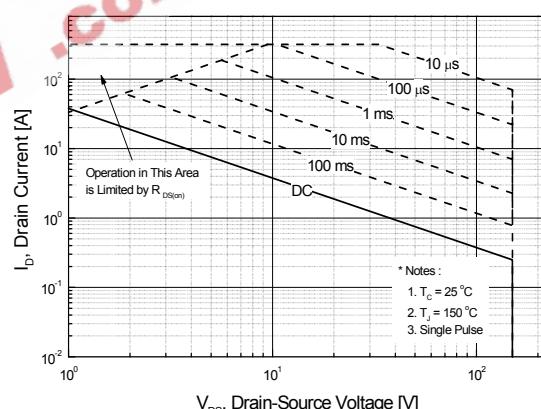
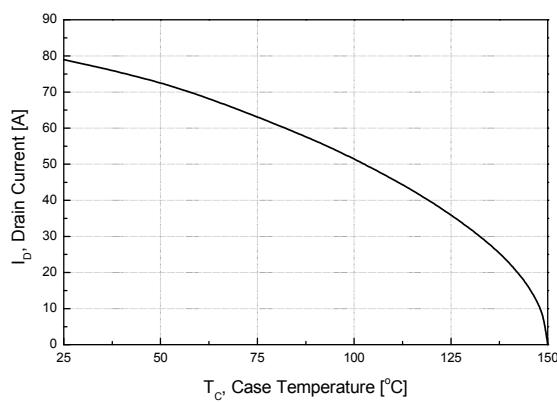


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FDP79N15

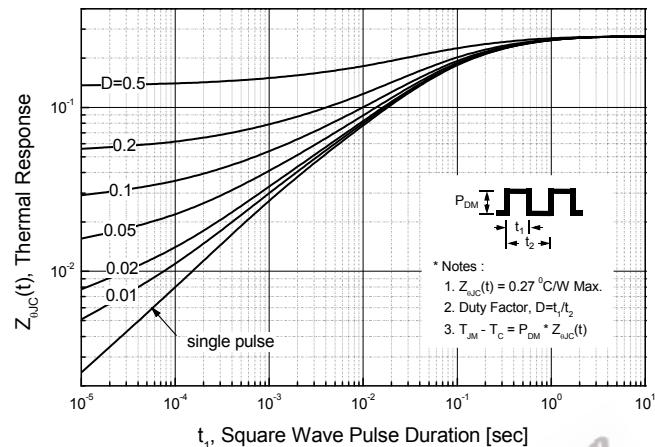
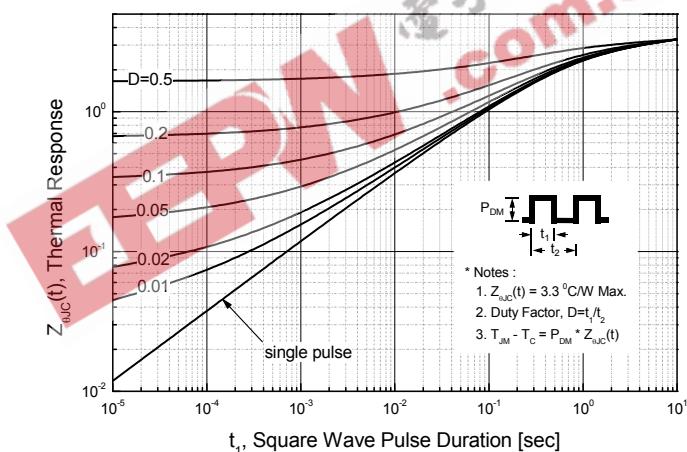
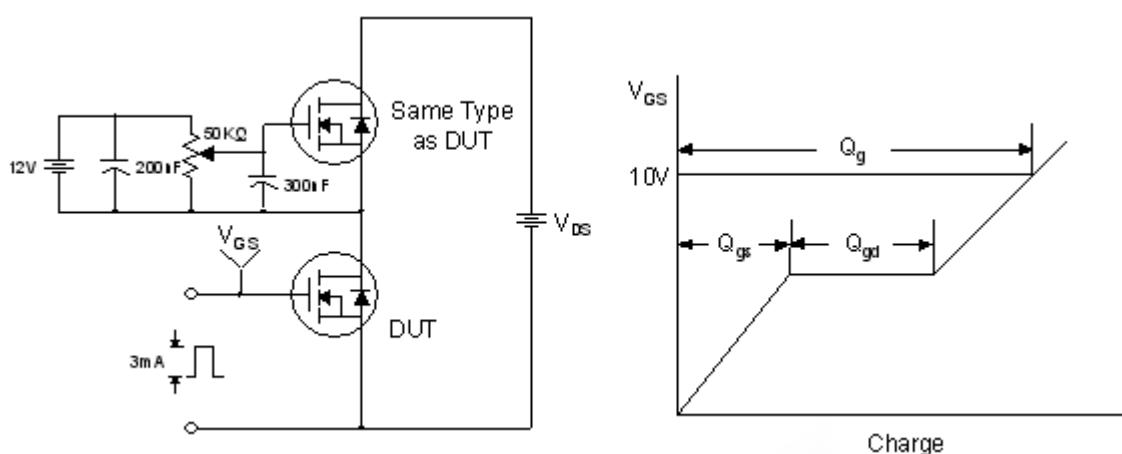
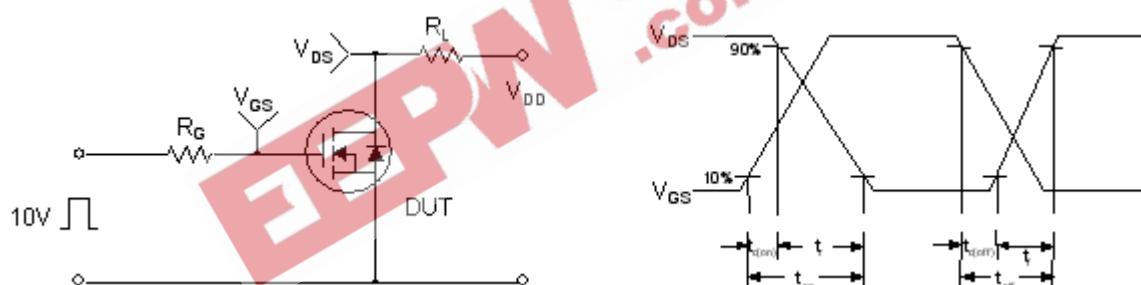
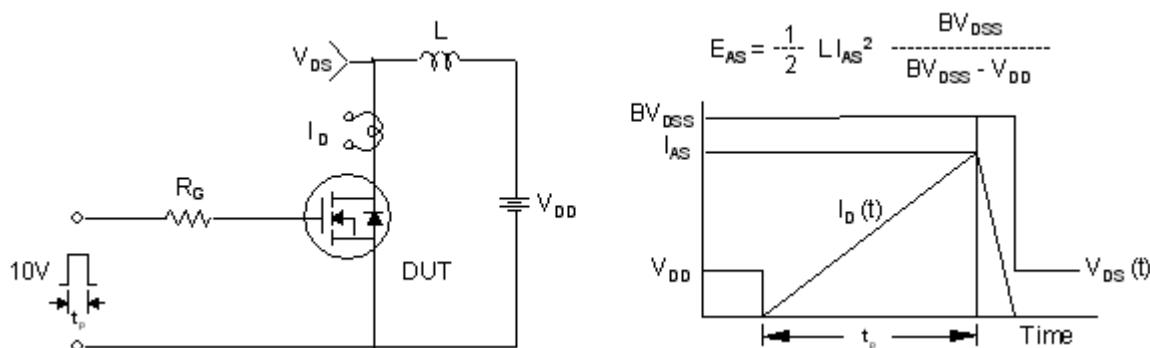
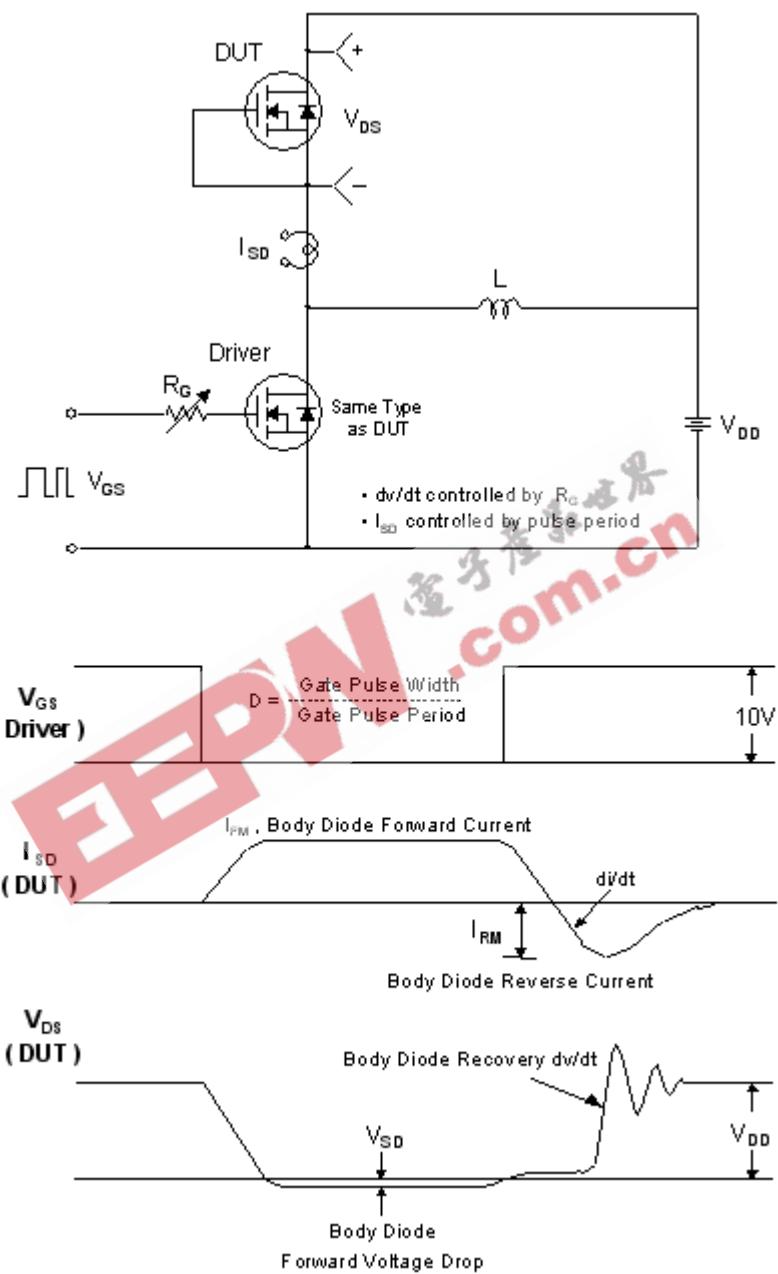


Figure 11-2. Transient Thermal Response Curve for FDPF79N15



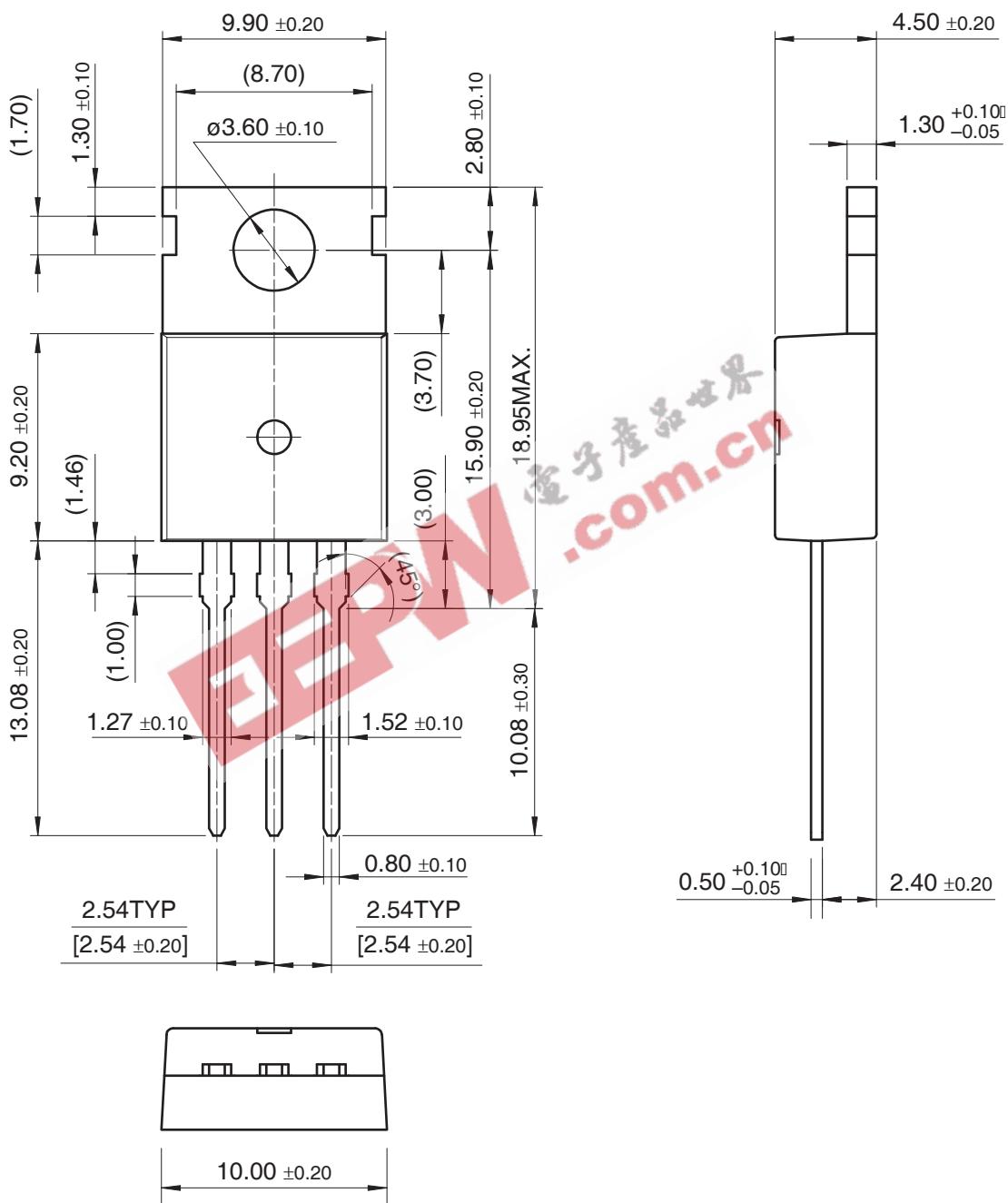
Gate Charge Test Circuit & Waveform**Resistive Switching Test Circuit & Waveforms****Unclamped Inductive Switching Test Circuit & Waveforms**

Peak Diode Recovery dv/dt Test Circuit & Waveforms

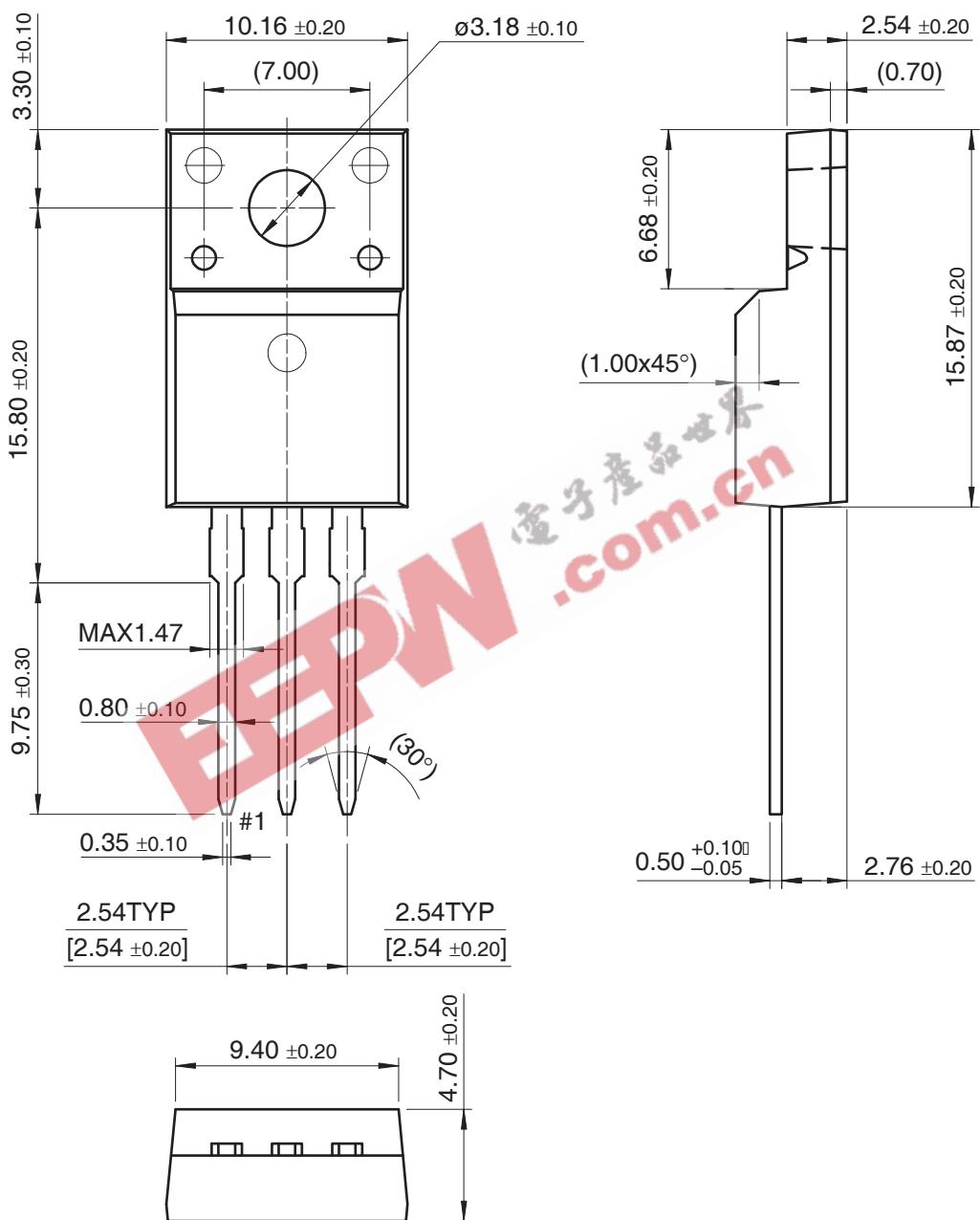


Mechanical Dimensions

TO-220



Dimensions in Millimeters

Mechanical Dimensions (Continued)**TO-220F**

Dimensions in Millimeters



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